

High Speed 10M bit/s Photocoupler

Product Description

The EMD2A611 is an optically coupled gate that combines a light emitting diode and an integrated high gain photo detector. The output of the detector IC is an open collector Schottky clamped transistor. The internal shield provides a guaranteed common mode transient immunity specification of 10,000 V/ μ s for the EMD2A611.

This unique design provides maximum AC and DC circuit isolation while achieving TTL compatibility. The photocoupler AC and DC operational parameters are guaranteed from -40°C to $+110^{\circ}\text{C}$, allowing trouble-free system performance.

The EMD2A611 is suitable for high-speed logic interfacing, input/output buffering, as line receivers in environments that conventional line receivers cannot tolerate and are recommended for use in extremely high ground or induced noise environments.

Features

- 10 kV/ μ s minimum Common Mode Rejection (CMR) at VCM = 1000V
- High speed: 10M bit/s typical

- VCC range: 4.5~5.5V
- LSTTL/TTL compatible
- Inverter logic type
- Low input current capability: 5 mA
- Guaranteed ac and dc performance over $-40^{\circ}\text{C} \sim +110^{\circ}\text{C}$.

Applications

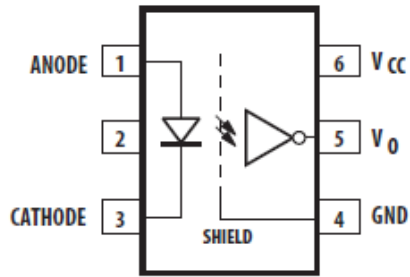
- Isolated line receiver
- Computer-peripheral interfaces
- Microprocessor system interfaces
- Digital isolation for A/D, D/A conversion
- Switching power supply
- Instrument input/output isolation
- Ground loop elimination
- Pulse transformer replacement
- Power transistor isolation in motor drives
- Isolation of high speed logic systems

Safety approved

- UL1577 recognized with 3750 Vrms for 1 minute for EMD2A611-SK and 5000 Vrms for 1 minute for EMD2A611-SL Certificate No. E529603
- IEC/EN/DIN EN 60747-5-5 Approved
 $V_{IORM} = 891 \text{ Vpeak}$ for EMD2A611-SK
 $V_{IORM} = 1140 \text{ Vpeak}$ for EMD2A611-SL
 Certificate No. 40055846
- CQC approved: GB4943.1-2011
 Certificate No. CQC22001358589

SCHEMATIC	PIN DEFINITION	PACKAGE
	<ol style="list-style-type: none"> 1. Anode 2. NC 3. Cathode 4. GND 5. VO 6. Vcc 	

Connection Diagram



Order Information

EMD2A611-00S###%FR1

- 00 Internal control Code
- S### SK06: LSOP-6 Package 7mm clearance
SL06: LSOP-6 Package 8mm clearance
- % E: RoHS & Halogen free package with VDE
N: RoHS & Halogen free package
- F -40 to 110°C temperature rating
- R1 Packing in Tape & Reel

Order, Mark & Packing Information

Package	Product ID	Mark	Packing
LSOP-6	EMD2A611-00SK06EFR1 EMD2A611-00SL06EFR1		Tape & Reel 3Kpcs
	EMD2A611-00SK06NFR1 EMD2A611-00SL06NFR1		

Absolute Maximum Ratings (Ta = 25°C unless otherwise specified)

Parameter	Symbol	Min	Max	Unit
Storage Temperature	Tstg	-55	125	°C
Operating Temperature	Topr	-40	110	°C
Average Forward Input Current(Note 1)	IF	-	20	mA
Reverse Input Voltage	VR	-	5	V
Input Power Dissipation	PI	-	45	mW
Supply Voltage	VCC	-	7	V
Output Collector Current	IO		50	mA
Output Collector Voltage	VO		7	V
Output Collector Power Dissipation	PI	-	85	mW
Lead Solder Temperature	Tsol	-	260	°C

Note 1: Peaking circuits may produce transient input currents up to 50 mA, 50-ns maximum pulse width, provided average current does not exceed 20 mA

Recommended Operation Condition

Parameter	Symbol	Min	Max	Unit
Operating Temperature	TA	-40	110	°C
Supply Voltage	VCC	4.5	5.5	V
Input Current High Level	IFLH	5	15	mA
Input Voltage Low Level	VFHL	-3.0	0.8	V
Fan Out (at RL = 1 KΩ)	N		5	TTL Loads
Output Pull-up Resistor	RL	330	4K	Ω

IEC/EN/DIN EN 60747-5-5 Insulation Characteristics

Description	Symbol	EMD2A611-SK	EMD2A611-SL	Unit
Climatic Classification	--	55/100/21	55/100/21	--
Pollution Degree (DIN VDE 0110/1.89)	--	2	2	--
Maximum Working Insulation Voltage	V_{IORM}	891	1140	V_{peak}
Input to Output Test Voltage, Method b (Note 2) $V_{IORM} \times 1.875 = V_{PR}$, 100% Production Test With $t_m = 1\text{sec}$, Partial discharge < 5pC	V_{PR}	1671	2137	V_{peak}
Input to Output Test Voltage, Method a (Note 2) $V_{IORM} \times 1.6 = V_{PR}$, 100% Production Test With $t_m = 10\text{sec}$, Partial discharge < 5pC	V_{PR}	1426	1824	V_{peak}
Highest Allowable Overvoltage (Transient Overvoltage $t_{ini} = 60\text{sec}$)	V_{IOTM}	6000	8000	V_{peak}
Safety-limiting values – maximum values allowed in the event of a failure				
Case Temperature	T_s	175	175	°C
Input Current	$I_s, INPUT$	150	150	mA
Output Power	$P_s, OUTPUT$	600	600	mW
Insulation Resistance at $T_s, V_{IO} = 500\text{V}$	R_s	$>10^9$	$>10^9$	Ω

Note 2 : Refer to the optocoupler section of the Isolation and Control Components Designer's Catalog, under Product Safety Regulations section, (IEC/EN/DIN EN 60747-5-5) for a detailed description of Method a and Method b partial discharge test profiles.
 These optocouplers are suitable for "safe electrical isolation" only within the safety limit data. Maintenance of the safety data shall be ensured by means of protective circuits. Surface mount classification is Class A accordance with CECC 00802.

Insulation and Safety-Related Specifications

Parameter	Symbol	EMD2A		Unit	Conditions
		611-SK	611-SL		
Minimum External Air Gap (External Clearance)	L(101)	7.0	8.0	mm	Measured from input terminals to output terminals, shortest distance through air.
Minimum External Tracking (External Creepage)	L(102)	8.0	8.0	mm	Measured from input terminals to output terminals, shortest distance path along body.
Tracking Resistance (Comparative Tracking Index)	CTI	>175	>175	V	DIN IEC 112/VDE 0303 Part 1.

Electrical Characteristics (DC)

All Typical values at $T_A = 25^\circ\text{C}$ and $V_{CC} = 5\text{ V}$, unless otherwise specified; all minimum and maximum specifications are at recommended operating condition.

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Condition
High Level Output Current	IOH	-	0.35	100	μA	$V_{CC} = 5.5\text{V}$, $V_O = 5.5\text{V}$, $V_F = 0.8\text{V}$
Input Threshold Current	ITH	-	1.0	5.0	mA	$V_{CC} = 5.5\text{V}$, $V_O = 0.6\text{V}$, $I_{OL} > 13\text{ mA}$
Low Level Output Voltage	VOL	-	0.25	0.6	V	$V_{CC} = 5.5\text{V}$, $I_F = 5\text{ mA}$, $I_{OL}(\text{Sinking}) = 13\text{ mA}$
High Level Supply Current	ICCH	-	5.6	7.5	mA	$V_{CC} = 5.5\text{V}$, $I_F = 0\text{ mA}$,
Low Level Supply Current	ICCL	-	5.2	10.5	mA	$V_{CC} = 5.5\text{V}$, $I_F = 10\text{ mA}$
Input Forward Voltage	VF	1.6	2.0	2.4	V	$I_F = 10\text{ mA}$
Input Reverse Breakdown Voltage	BVR	5	-	-	V	$I_R = 10\ \mu\text{A}$
Input Capacitance	CIN	-	60	-	pF	$f = 1\text{ MHz}$, $V_F = 0\text{V}$

Switching Specification (AC)

All Typical values at $T_A = 25^\circ\text{C}$ and $V_{CC} = 5\text{ V}$, $I_F = 7.5\text{mA}$, unless otherwise specified; all minimum and maximum specifications are at recommended operating condition.

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Condition
Propagation Delay Time to High Output Level	tPLH	-	60	75	ns	$V_{CC} = 5\text{V}$, $I_F = 7.5\text{ mA}$, $R_L = 350\Omega$, $C_L = 15\text{ pF}$
Propagation Delay Time to Low Output Level	tPHL	-	35	75		
Pulse Width Distortion	tPHL-tPLH	-	25	40		
Propagation Delay Skew	tPSK	-	-	50		
Output Rise Time (10 to 90%)	tr	-	30	-		
Output Fall Time (90 to 10%)	tf	-	3	-		
Common mode transient immunity at high level output (Note 3)	CMH	10	15	-	kV/ μs	$V_{CC} = 5\text{V}$, $I_F = 0\text{ mA}$, $V_O(\text{MIN}) = 2\text{V}$, $R_L = 350\Omega$, $V_{CM} = 1000\text{V}$
Common mode transient immunity at low level output (Note 4)	CML	10	15	-	kV/ μs	$V_{CC} = 5\text{V}$, $I_F = 7.5\text{ mA}$, $V_O(\text{MAX}) = 0.8\text{V}$, $R_L = 350\Omega$, $V_{CM} = 1000\text{V}$

Note 3 : CMH is the maximum tolerable rate of rise of the common mode voltage to assure that the output will remain in a high logic state (that is, $V_{OUT} > 2.0\text{V}$).

Note 4 : CML is the maximum tolerable rate of fall of the common mode voltage to assure that the output will remain in a low logic state (that is, $V_{OUT} > 0.8\text{V}$).

Isolation characteristic

All Typical values at $T_A = 25^\circ\text{C}$ and $V_{CC} = 5\text{V}$, unless otherwise specified; all minimum and maximum specifications are at recommended operating condition.

Parameter	Symbo	Device	Min.	Typ.	Max.	Unit	Test Condition
Withstand Insulation Test Voltage (Note 5, 6)	V_{ISO}	EMD2A611-SK	5000	-	-	V	RH \leq 40%-60%, $t = 1\text{min}$, $T_A = 25^\circ\text{C}$
		EMD2A611-SL					
Input-Output Resistance (Note 5)	R_{I-O}	-	-	10^{12}	-	Ω	$V_{I-O} = 500\text{V DC}$

Note 5: Device is considered a two terminal device: pins 1, 2, 3 are shorted together and pins 4, 5, 6 are shorted together.

Note 6: According to UL1577, each photo coupler is tested by applying an insulation test voltage 6000VRMS for one second (leakage current less than 10uA). This test is performed before the 100% production test for partial discharge.

Typical Performance Curves & Test Circuits

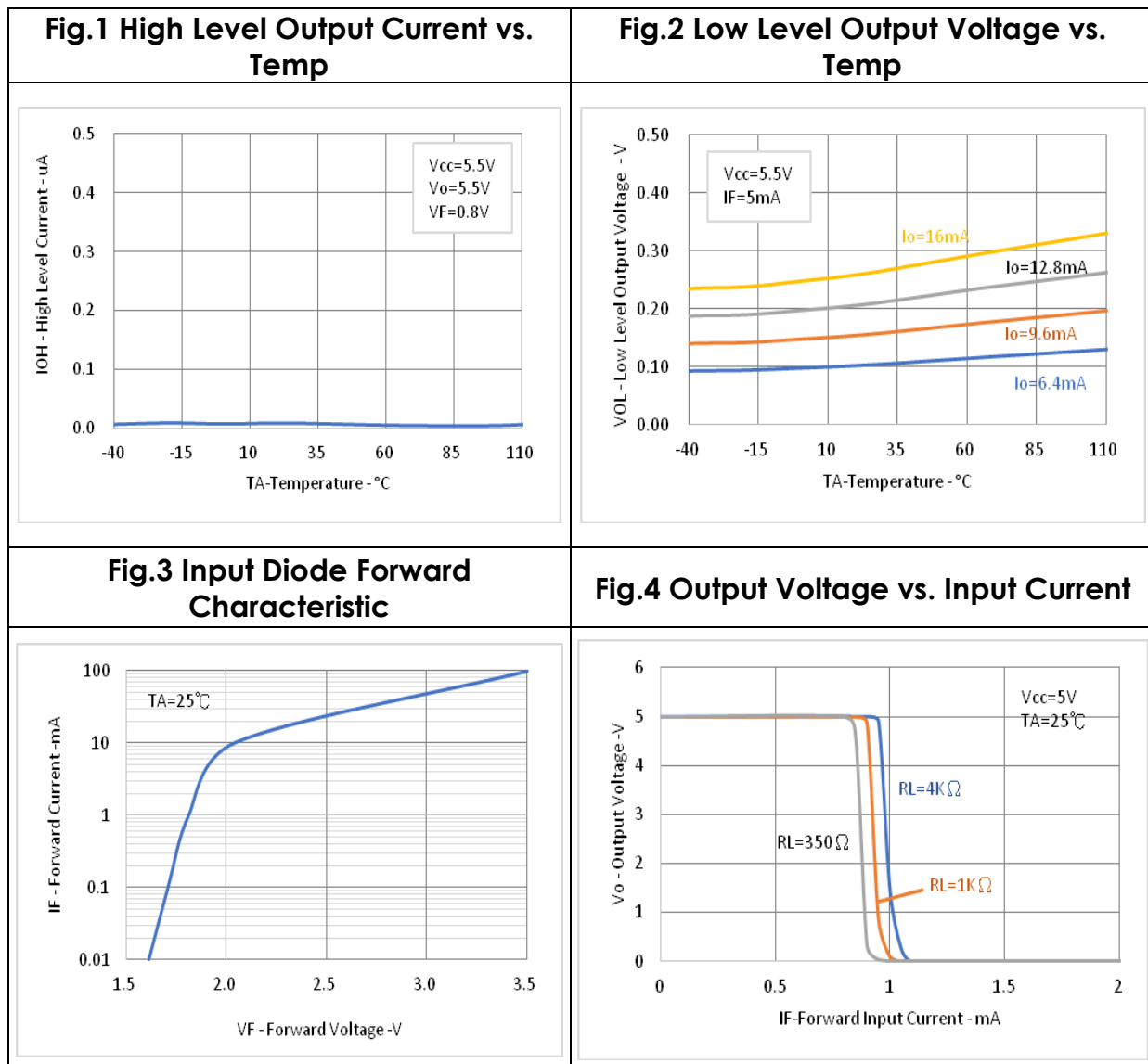


Fig.5 Low Level Output Current vs. Temp

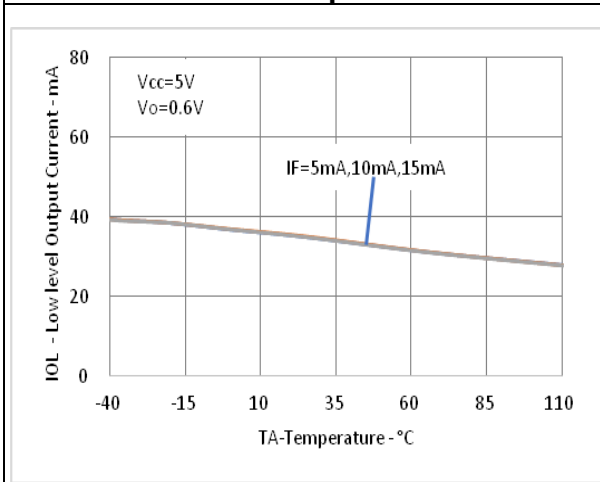


Fig.6 Propagation Delay vs. Temperature

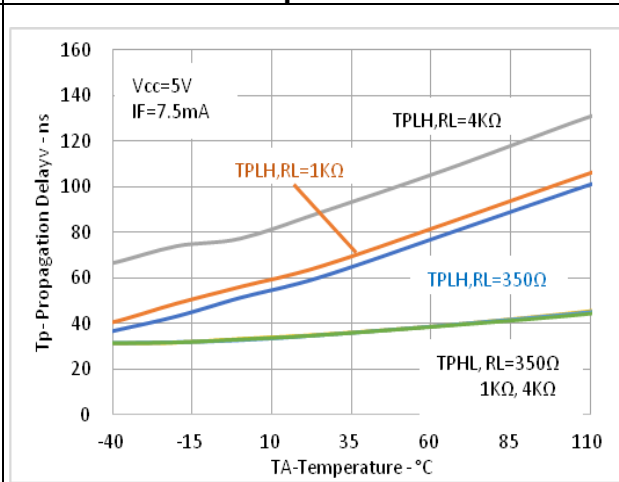


Fig.7 Propagation Delay vs. Input Current

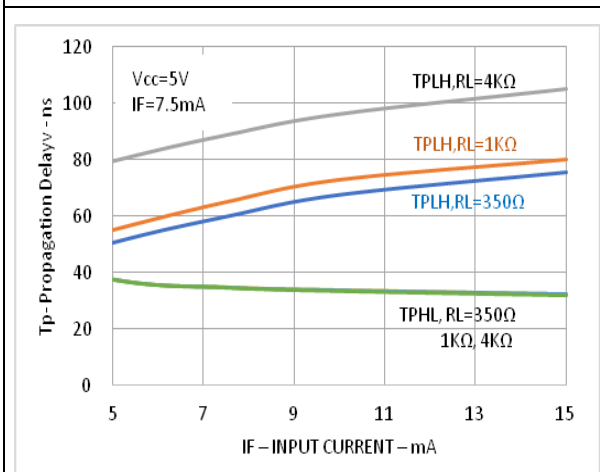


Fig.8 Pulse Width Distortion vs. Temperature

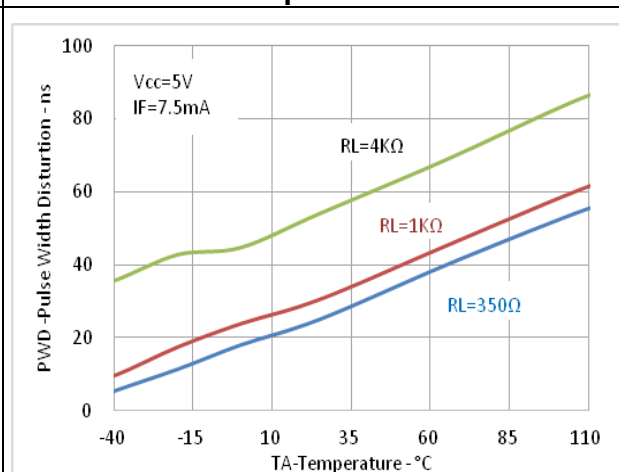


Fig.9 Rise and Fall Time vs. Temperature

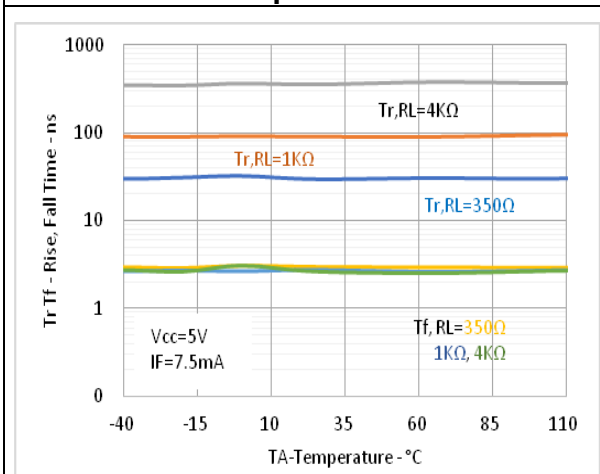
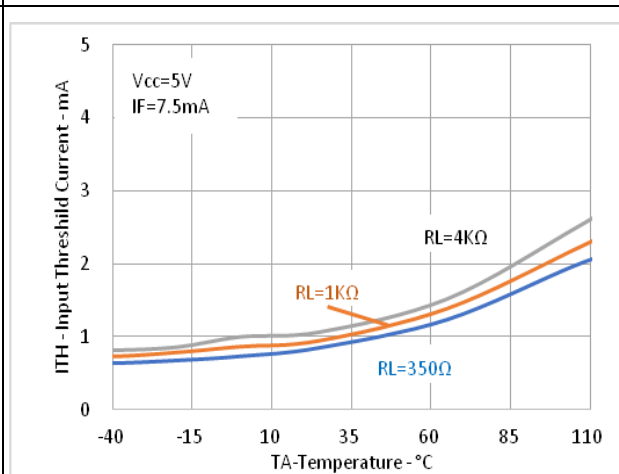
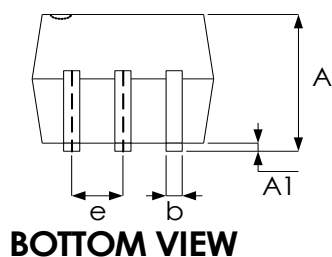
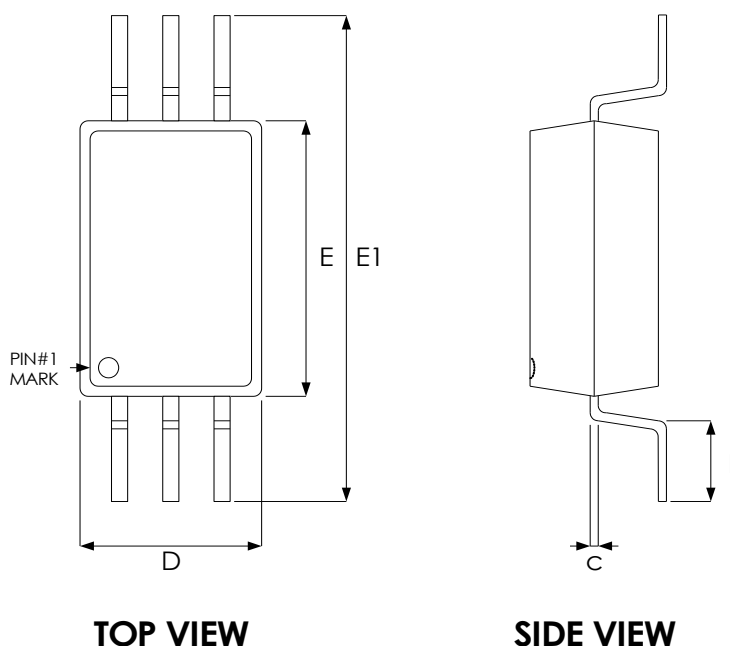


Fig.10 Input Threshold Current vs. Temp

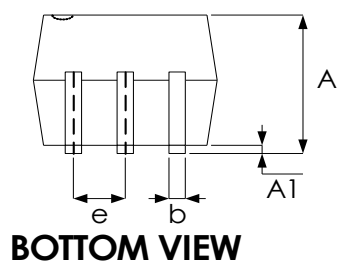
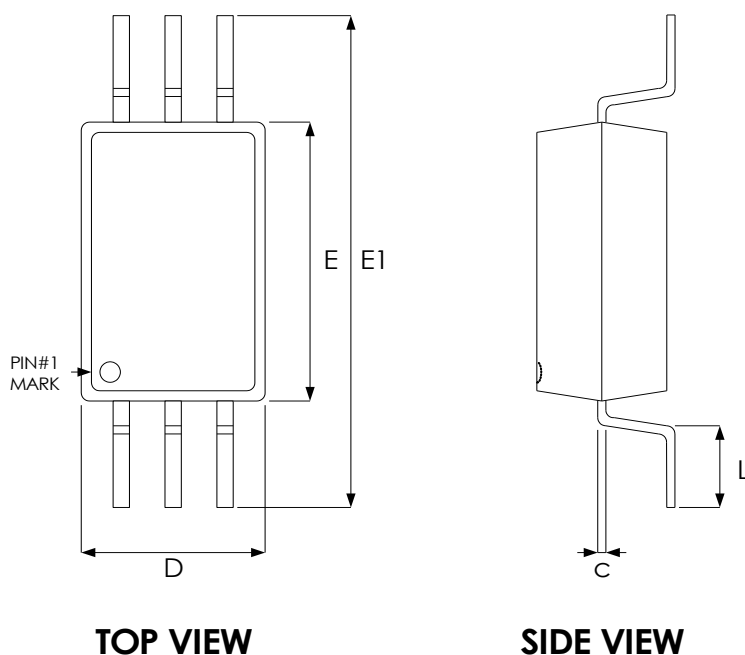


Package Outline Drawing
L-SOP 6L (277mil, 7mm clearance)



Symbol	Dimension in mm	
	Min.	Max.
A	1.70	2.30
A1	0.10	0.30
b	0.30	0.50
c	0.20	0.30
D	4.20	4.80
E	6.50	7.10
E1	9.40	10.00
e	1.27 BSC	
L	0.70	1.20

Package Outline Drawing
L-SOP 6L (277mil, 8mm clearance)



Symbol	Dimension in mm	
	Min.	Max.
A	1.70	2.30
A1	0.10	0.30
b	0.30	0.50
c	0.20	0.30
D	4.20	4.80
E	6.51	7.11
E1	11.20	11.80
e	1.27 BSC	
L	0.50	1.00

Revision History

Revision	Date	Description
0.1	2023.02.03	Preliminary version
0.2	2023.06.01	Update: 1. High Speed Information (page1) 2. Insulation Characteristics (page4)

Important Notice

All rights reserved.

No part of this document may be reproduced or duplicated in any form or by any means without the prior permission of ESMT.

The contents contained in this document are believed to be accurate at the time of publication. ESMT assumes no responsibility for any error in this document, and reserves the right to change the products or specification in this document without notice.

The information contained herein is presented only as a guide or examples for the application of our products. No responsibility is assumed by ESMT for any infringement of patents, copyrights, or other intellectual property rights of third parties which may result from its use. No license, either express, implied or otherwise, is granted under any patents, copyrights or other intellectual property rights of ESMT or others.

Any semiconductor devices may have inherently a certain rate of failure. To minimize risks associated with customer's application, adequate design and operating safeguards against injury, damage, or loss from such failure, should be provided by the customer when making application designs.

ESMT's products are not authorized for use in critical applications such as, but not limited to, life support devices or system, where failure or abnormal operation may directly affect human lives or cause physical injury or property damage. If products described here are to be used for such kinds of application, purchaser must do its own quality assurance testing appropriate to such applications.